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(54) **AUTOMATIC ASSIGNMENT OF DEVICE DEBUG COMMUNICATION PINS**

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See application file for complete search history.

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(57) **ABSTRACT**

An apparatus includes a debugger circuit, debug pins, and a test controller circuit. The test controller circuit is configured to, in a programming mode, determine a subset of the debug pins used in programming the apparatus. The test controller circuit is further configured to save a designation of the subset of the debug pins. The test controller circuit is further configured to, in a test mode subsequent to the programming mode, use the designation to route the subset of the debug pins used in programming the apparatus to the debugger circuit for debug input and output with the server.

15 Claims, 3 Drawing Sheets